

Notice of References Cited			Application/Control No. 10/588,833	Applicant(s)/Patent Under Reexamination LIEBER ET AL.	
			Examiner DAREN WOLVERTON	Art Unit 2813	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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C	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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V	Zhang, Z. et al. "Electrically robust ultralong nanowires of NiSi, Ni ₂ Si, and Ni ₃₁ Si ₁₂ ", 24 January 2006, Applied Physics Letters 88, 043104 (2006)
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